Docket No.: MUH-12656

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : UDO HARTMANN

Filed : CONCURRENTLY HEREWITH

Title : CONFIGURATION FOR TESTING SEMICONDUCTOR DEVICES

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

In accordance with 37 C.F.R. 1.98 copies of the following patents and/or publications are submitted herewith:

U.S. Patent No. 6,297,659 B1 (Saito), dated October 2, 2001;

German Translation DE 693 07 965 T2 (Abraham et al.), dated January 26, 1994, of European Patent EP 0 580 473 B1, and English abstract thereof;

Patent Abstracts of Japan 07218552 A (Takahide et al.), dated August 18, 1995;

Börschlein, H.: "Präzisionsmessung hoher Gleichströme" [Precision Measurement of High Direct Currents], Siemens Magazine, May 1958, pp. 323-325.

If no translation of pertinent portions of any foreign language patents or publications mentioned above is included with the aforementioned copies of those applications, patents and/or publications, it is because no existing translation is readily available to the applicant.

Respectfully submitted,

For Applicant

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| FORM PTO-1449 (SUBSTITUTE) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE | | | | Attorney Docket No.: MUH-12656 Appl. No.: | | | | |
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| INFORMATION DISCLOSURE STATEMENT BY APPLICANT (37 CFR 1.98(b)) | | | | Applicant: UDO HARTMANN Filing Date: June 27, 2003 Group Art Unit: | | | | |
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| EXAMINER INITIALS | | PATENT NO. | DATE | PATENTEE | CLASS | SUB CLASS | | ING ATE |
| | Α | 6,297,659 B1 | 10/2/01 | Saito | | | | |
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| ОТН | ER DO | OCUMENTS (Incli | uding Auth | nor, Title, Date, Pe | rtinent Pa | ges, etc. |) | |
| | | Börschlein, H.: "Präzisionsmessung hoher Gleichströme" [Precision Measurement of High Direct Currents], Siemens Magazine, May 1958, pp. 323-325 | | | | | | |
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